Se	arch	Note	<b>3</b> S	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/771,576	KOO ET AL.
Examiner	Art Unit
TAN TRINH	2684

SEARCHED			
Class	Subclass	Date	Examiner
455	522	8/18/2006	π
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370	318		
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375	148		
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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706	DYB		·
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST	8/18/2006	π	
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<b>#</b>	4/24/07	7.7.	
VO, NGUYEN	8/17/2006	π	
NICK CORSARO	8/18/2006	π	
JEARCH			
SEARCH/	4/24/07	7.7	
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